

Beamtest of Non-Irradiated and Irradiated ATLAS SCT
Microstrip Modules at KEK

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Non-irradiated and irradiated ATLAS SCT barrel and forward modules equipped with ABCD chips were tested with the 4 GeV/c pion beams at KEK. Pulse shapes confirmed the peaking time of the amplifier to be less than 23 ns and broadening of the signals of the irradiated modules. Median charge saturated to 3.5 fC fast in the non-irradiated and slowly in the irradiated modules as a function of bias voltage. Signal/Noise ratios, using the noises from the in-situ calibration, were 15 in the non-irradiated, and 10 at 400V in the irradiated modules.

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